Form PTO 1449				ATTY DOCKET NO.		SERIAL NO. NEW APPLICATION			
(Modified)		PATENT AND TRA	ADEMARK OFFICE	239876US2					
LIST OF REFERENCES CITED BY APPLICANT			APPLICANT						
			Kouichi MOCHIZUKI						
				FILING DATE		GROUP			
				HEREWITH					
				U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS			
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO			
DP	AO	6-37222	02/10/94	Japan (with English Abstract)				x	
DP	AP	7-131316	05/19/95	Japan (with English Abstract)				×	
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 239876US2		SERIAL NO. 10/614,032			
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				FILING DATE		GROUP			
				July 8, 2003		2816			
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DP	AO	10-229671	08/25/1998	JAPAN (with English Abstract)				X	
DP	AP	2000-0014865	07/25/2000	KOREA (with English translation)					
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Form PTO 1449	U.S. DEPARTMENT OF COMMERCE		OF COMMERCE	ATTY DOCKET NO.			SERIAL NO.			
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EXAMINER INITIAL		DOCUMBLY NUMBER TRA	DEM ATE	NAME	CLASS	SUB CLAS		LING DATE PPROPRIATE		
DP	AA	5,621,257	04/15/1997	Kazuto KAWAKAMI						
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- Th	AO	7-336996	12/22/1995	JAPAN (with English Abstract and corr.	US 5,621	,25/)		X		
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